

**High Resolution High Accuracy Semicontact / Noncontact / Force Modulation AFM Cantilevers HA FM series with Au tip conductive coating, each chip has 2 cantilevers, resonant frequency 114 kHz / 77 kHz, force constant 6 N/m / 3.5 N/m**

Art. ID	TIPS-HA_FM/Au/300
Unit	300 separated chips
Deliverydetails	No Dangerous Good /not restricted

Description

High Resolution High Resonant Frequency AFM Cantilevers HA\_FM/Au series are designed for Semicontact ( Intermittent ), Noncontact and electrical applications (SKM, SCM, SRIM, EFM, LAO Lithography). Each probe has 2 rectangular cantilevers. Typical Resonant Frequency 114kHz / 77kHz (dispersion  $\pm 10\%$ ). Typical Force Constant 12N/m / 3.5N/m (dispersion  $\pm 20\%$ ). Cantilever has Au tip and reflective side coatings. Probes are also available without tip coating / High Accuracy composite ETALON probes combine the main features allowing to obtain high quality AFM images: /// Sharp tip - curvature radius < 10 nm. /// Resonance frequency, specified with high accuracy -  $\pm 10\%$  within a wafer. /// Special chip geometry with vertical sidewalls for convenient operating. /// High aspect ratio tip. /// Enhanced back-side reflection of the cantilever. /// Cost effective price